

## Supporting Information

### Origin of efficiency enhancement in Nb<sub>2</sub>O<sub>5</sub> coated titanium dioxide nanorod based dye sensitized solar cells.

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*Contribution to the special number of the International Conference on Ordered 1  
Dimensional Nanostructures for Photovoltaics, from 12 to 15 september 2010,  
Mallorca, Spain*

#### Recombination resistance and Chemical capacitance vs potential:

For most of the cases, the charge transfer resistance arising at the porous nanostructured electrode in contact with liquid electrolyte may be described by using a recombination resistance (or charge transfer resistance),  $R_{rec}$ , that depends on the Fermi level as:<sup>1,2</sup>

$$R_{rec} = R_0 \exp \left[ \beta \frac{E_{redox} - E_{Fn}}{k_B T} \right] \quad (S1)$$

in which  $R_0$  is a constant indicating the onset of recombination,  $\beta$  is the recombination parameter (also named charge transfer coefficient) governing the non linear recombination,  $k_B$  is the Boltzmann constant,  $T$  the temperature,  $E_{Fn}$  the Fermi level of electrons in the semiconductor and  $E_{redox}$  the redox potential (i.e. the Fermi level of holes in the electrolyte). The Fermi level voltage is  $V_F = (E_{Fn} - E_{redox})/q$ , with  $q$  the electron charge, and thus Eq. (S1) may be written as Eq. (1).

The capacitance of these nanostructures, when they have a low doping, is described by the equation:<sup>3</sup>

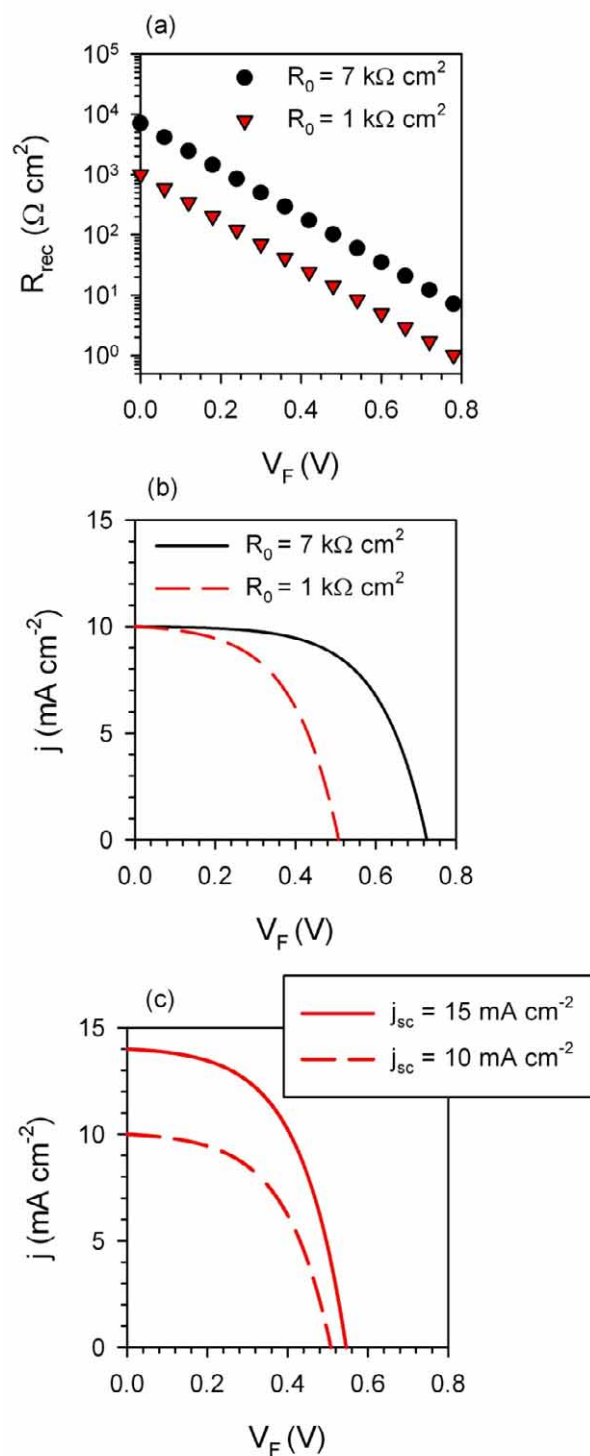
$$C_\mu = \frac{N_c q^2}{k_B T} \exp \left[ \frac{E_{Fn} - E_C}{k_B T_0} \right] \quad (S2)$$

$C_\mu$  is known as chemical capacitance and describes the density of states (DOS) of the nanostructured photoanode at energy levels below the conduction band ( $E_C$ ) given by the tail of the Boltzmann distribution. For a given number of states below the conduction band,  $N_c$ , this DOS is determined by the tail parameter  $T_0$ , which has units of temperature, and by the position of the conduction band. Eq. (S3) is usually written in terms of  $\alpha = T/T_0$  and of  $V_F$ , yielding:

$$C_\mu = C_0 \exp \left[ \alpha \frac{qV_F}{k_B T} \right] \quad (S3)$$

### Effects of recombination resistance and photocurrent in $j$ - $V$ curves

Eqs. (6) and (7) generate the  $j$ - $V$  curves shown in Fig. S1. The larger  $R_0$  (smaller  $j_0$ ), produces a larger  $R_{rec}$  as plot in Fig. S1(a) and, for the same  $j_{sc}$ , a larger  $V_{oc}$  as may be seen in Fig. S1(b). For the same  $R_0$ , an increase in  $j_{sc}$  produces a larger  $V_{oc}$ , as shown in Fig. S1(c).



**Fig. S1:** (a) Simulation of recombination resistance with  $\beta = 0.23$ ,  $R_0 = 7 \text{ k}\Omega \text{ cm}^{-2}$  (circles) and  $R_0 = 1 \text{ k}\Omega \text{ cm}^{-2}$  (triangles). (b)  $j$ - $V$  curves simulated from the simulated resistances in (a) with  $j_{\text{sc}} = 10 \text{ mA cm}^{-2}$ . (c)  $j$ - $V$  curves simulated from the simulated resistance with  $R_0 = 1 \text{ k}\Omega \text{ cm}^{-2}$ ,  $j_{\text{sc}} = 15 \text{ mA cm}^{-2}$  (solid line) and  $j_{\text{sc}} = 10 \text{ mA cm}^{-2}$  (dashed line).

## References

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